



**2023 IEDM Conference Theme**  
**Devices for a Smart World Built**  
**Upon 60 Years of CMOS**



# 2023 IEEE International Electron Devices Meeting

December 9-13, 2023

**IEDM is pleased to announce increased technical focus in the area of:**

## **Reliability of Systems & Devices (RSD)**

### **Topics**

Papers are solicited in the following themes of interest:

- Component level of FEOL/MEOL/BEOL reliability model
- Robustness and security of electronic circuits and systems
- Reliability of conventional and emerging memories
- Circuits, systems-level reliability, and aging
- Thermal and PID/charging management in existing and novel process integration
- Reliability of RF/mm-wave/5G in high-frequency applications
- Reliability of devices, circuits, and systems for more-than-Moore applications, automotive, aerospace and bio-applications (BioFETs, DNA detection, etc.)
- Reliability of cryogenic devices for future quantum computing applications

New or trending areas include:

- Reliability of new materials and/or new architectures for transistors
- Reliability of advanced 2.5D/3D IC advanced package
- Design for testing (DFT) / Design for reliability (DFR) solutions for improved reliability

### **Paper Submission**

**Submission deadline: July 13th**  
**Single submission of final, four-page paper**

### **For More Information**

**IEDM Online:** [ieee-iedm.org](http://ieee-iedm.org)

**Social Networks:**  
[ieee-iedm.org/social-media](http://ieee-iedm.org/social-media)

